

100V N-SGT Enhancement Mode MOSFET

General Description

APG80N10NF use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness and suitable to use in

Features

Low RDS(on) & FOM

Extremely low switching loss

Excellent stability and uniformity or Invertors

Applications

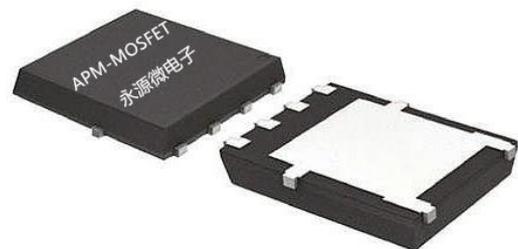
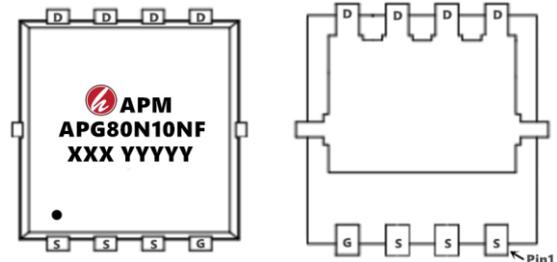
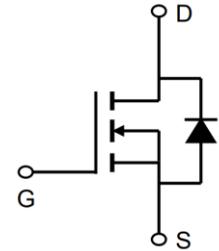
Consumer electronic power supply

Motor control

Synchronous-rectification

Isolated DC

Synchronous-rectification applications



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
APG80N10NF	DFN5*6-8	APG80N10NF XXX YYYY	5000

Absolute Maximum Ratings at T_J=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	100	V
VGS	Gate-Source Voltage	±20	V
I _D @T _A =25°C	Continuous Drain Current ¹	80	A
I _D @T _A =70°C	Continuous Drain Current ¹	62	A
IDM	Pulsed Drain Current ²	240	A
EAS	Single Pulse Avalanche Energy ³	120	mJ
IAS	Avalanche Current	15	A
P _D @T _A =25°C	Total Power Dissipation ⁴	135	W
TSTG	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C
R _{θJA}	Thermal Resistance Junction-Ambient ¹ (t≤10s)	54	°C/W
R _{θJA}	Thermal Resistance Junction-Ambient ¹	62	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	0.84	°C/W

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Electrical Characteristics at $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	100	---	---	V
RDS(ON)	Static Drain-Source On-Resistance ²	$V_{GS}=10V, I_D=13.5A$	---	6.6	8	m Ω
	Static Drain-Source On-Resistance ²	$V_{GS}=4.5V, I_D=11.5A$	---	8.7	10.5	
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	1.2	---	2.3	V
IDSS	Drain-Source Leakage Current	$V_{DS}=80V, V_{GS}=0V, T_J=25^\circ\text{C}$	---	---	1	uA
		$V_{DS}=80V, V_{GS}=0V, T_J=55^\circ\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	± 100	nA
gfs	Forward Transconductance	$V_{DS}=5V, I_D=13.5A$	---	75	---	S
Qg	Total Gate Charge (10V)	$V_{DS}=50V, V_{GS}=10V, I_D=13.5A$	---	45	---	nC
Qg	Total Gate Charge (4.5V)		---	19.3	---	
Qgs	Gate-Source Charge		---	9.5	---	
Qgd	Gate-Drain Charge		---	4.8	---	
Td(on)	Turn-On Delay Time	$V_{DD}=50V, V_{GS}=10V, R_G=3\Omega, I_D=13.5A$	---	10	---	ns
Tr	Rise Time		---	6.5	---	
Td(off)	Turn-Off Delay Time		---	45	---	
Tf	Fall Time		---	7.5	---	
Ciss	Input Capacitance	$V_{DS}=50V, V_{GS}=0V, f=1\text{MHz}$	---	3320	---	pF
Coss	Output Capacitance		---	605	---	
Crss	Reverse Transfer Capacitance		---	20	---	
IS	Continuous Source Current ^{1,5}	$V_G=V_D=0V, \text{Force Current}$	---	---	5	A
VSD	Diode Forward Voltage ²	$V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$	---	---	1.1	V
trr	Reverse Recovery Time	$I_F=13.5A, di/dt=100A/\mu s, T_J=25^\circ\text{C}$	---	33	---	nS
Qrr	Reverse Recovery Charge		---	150	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch 2 FR-4 board with 20Z copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=25V, V_{GS}=10V, L=0.3mH, I_{AS}=15A$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation

Typical Characteristics

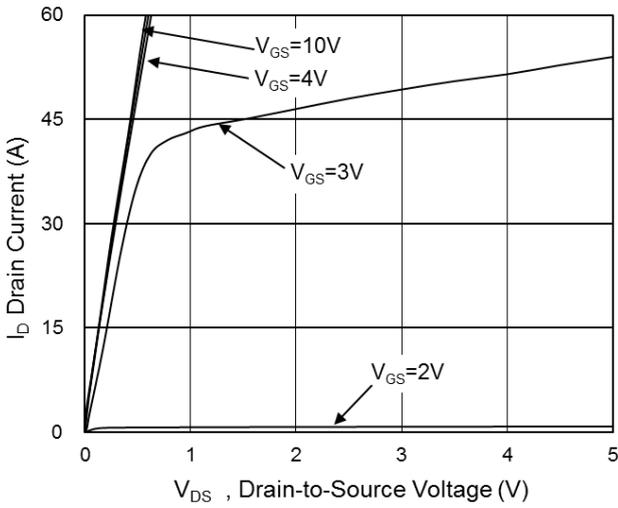


Fig.1 Typical Output Characteristics

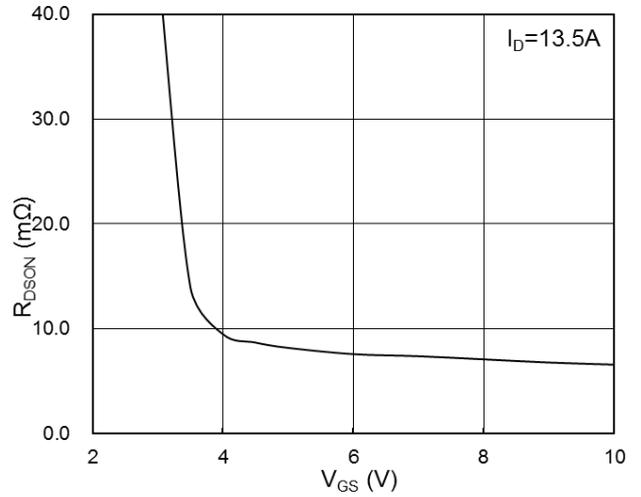


Fig.2 On-Resistance vs. G-S Voltage

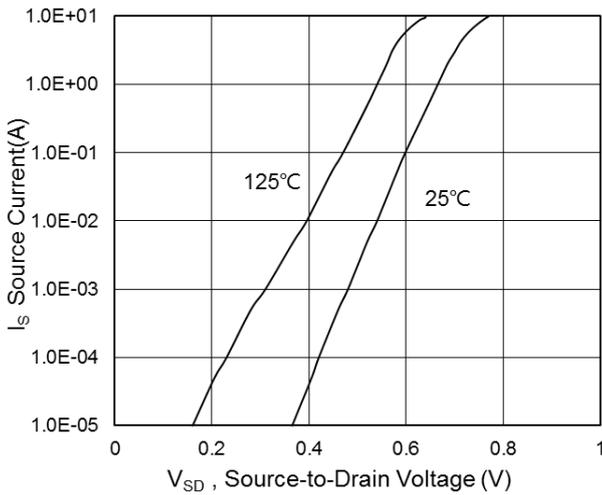


Fig.3 Source-Drain Forward Characteristics

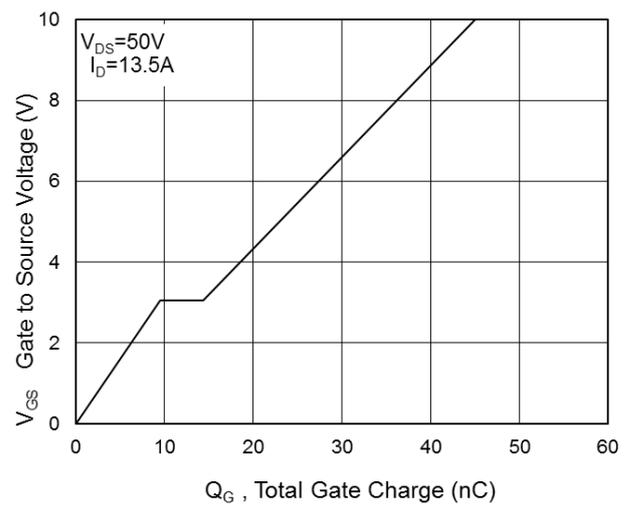


Fig.4 Gate-Charge Characteristics

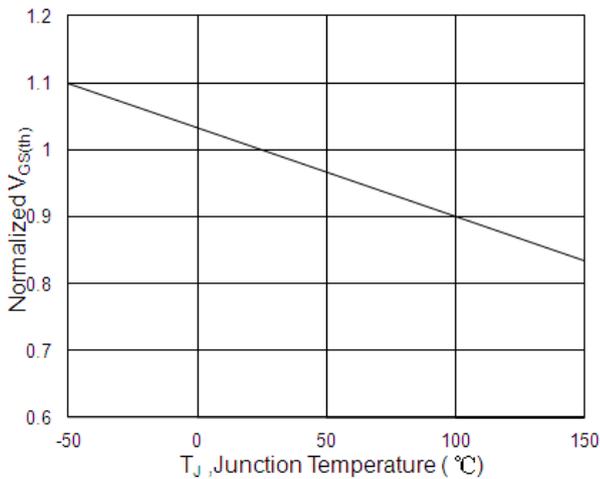


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

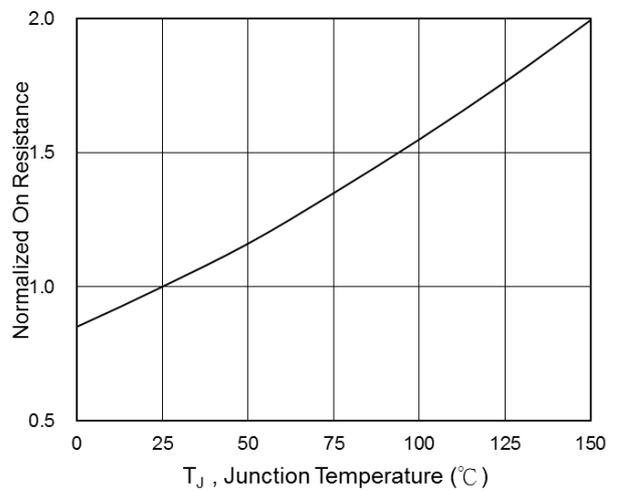


Fig.6 Normalized $R_{DS(on)}$ vs. T_J



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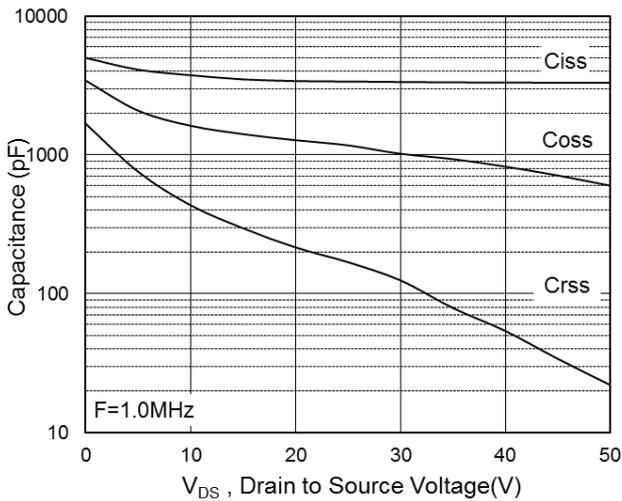


Fig.7 Capacitance

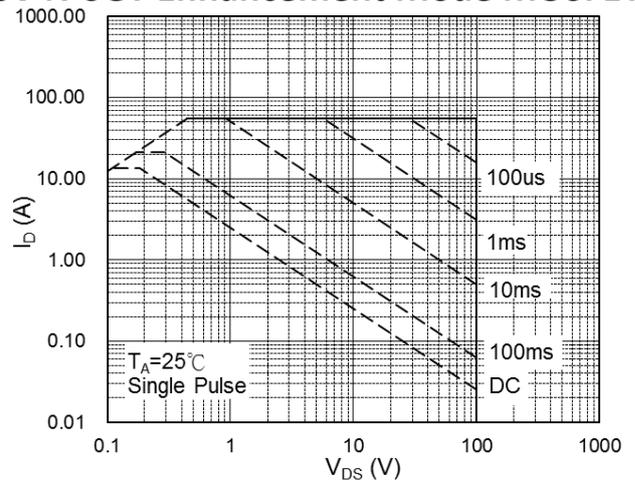


Fig.8 Safe Operating Area

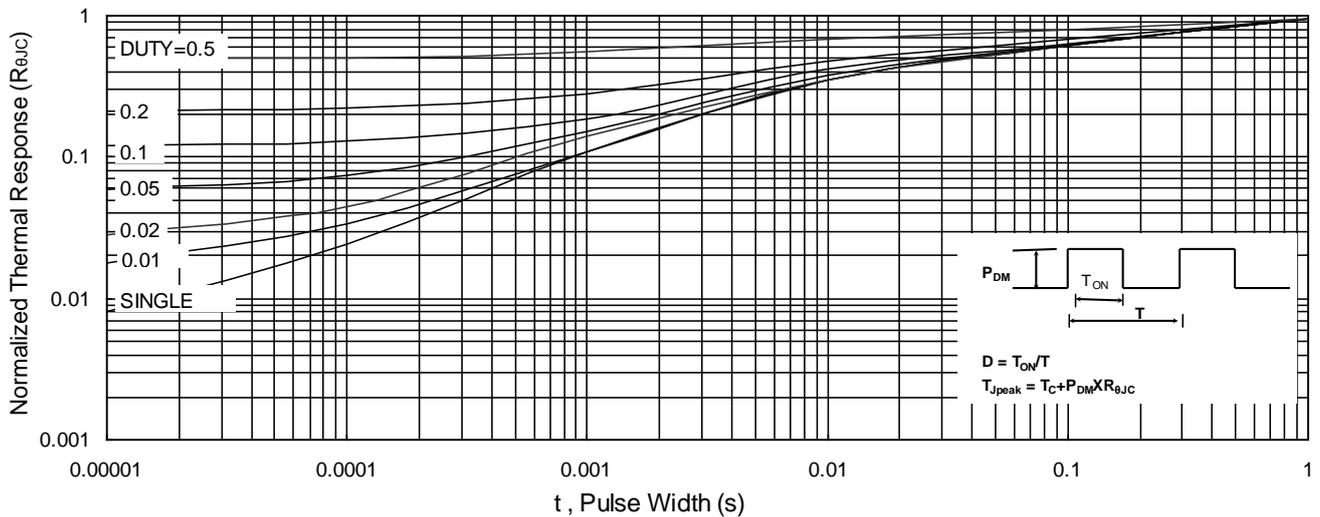


Fig.9 Normalized Maximum Transient Thermal Impedance

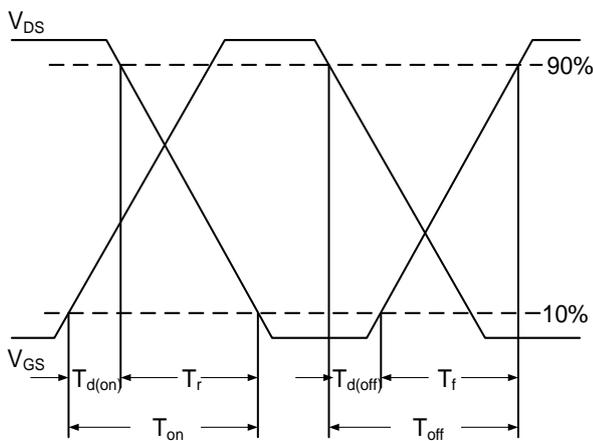


Fig.10 Switching Time Waveform

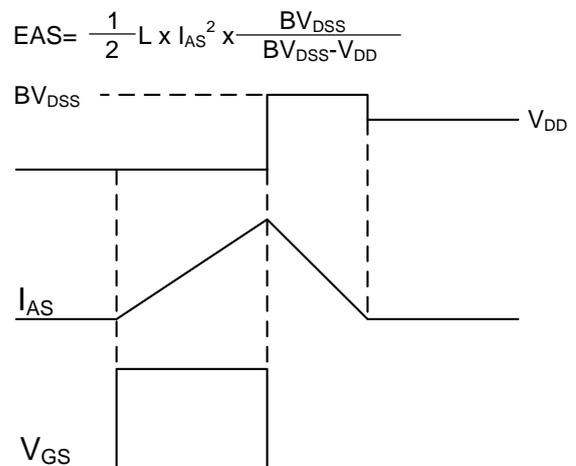
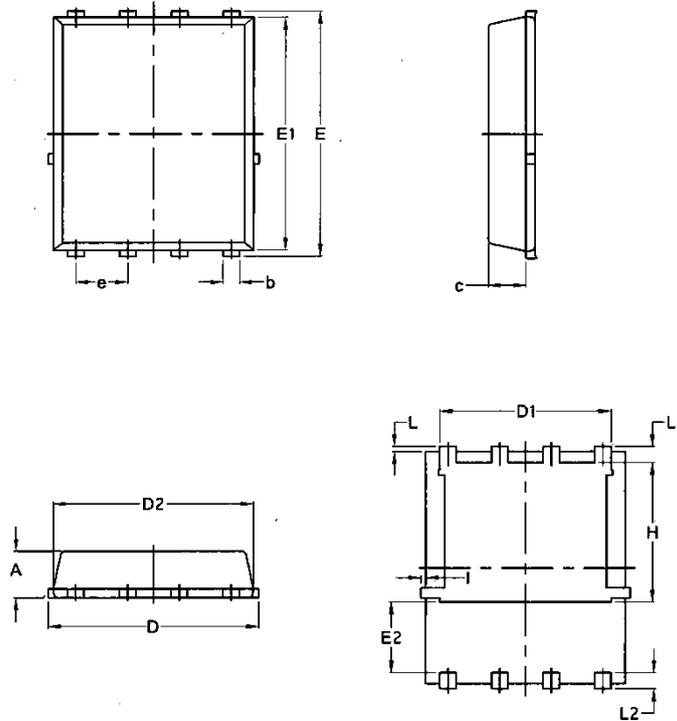


Fig.11 Unclamped Inductive Switching Waveform

Package Mechanical Data-DFN5*6-8L-JQ Single



Symbol	Common			
	mm		Inch	
	Min	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070

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Edition	Date	Change
Rve1.0	2019/12/1	Initial release

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